

ABSTRACT OF THE DISCLOSURE

A non-volatile storage device on a memory module comprising a plurality of memory devices is used to store the locations of defective parts on the memory module, such as data query ("DQ") terminals, identified during a testing procedure. After testing, the non-volatile storage device, such as an electrically erasable programmable read only memory ("EEPROM"), may be accessed to determine specific memory devices such as dynamic random access memory ("DRAM") which need to be repaired or replaced rather than re-testing the specific memory module.

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